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P1 98.2



MOS FIELD EFFECT POWER TRANSISTOR 2SK1758

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK1758 is N-channel MOS Field Effect Transistor designed for high voltage switching applications.

FEATURES

- Low On-state Resistance
 RDS(on) = 4.2 Ω (VGS = 10 V, ID = 1 A)
- Low Ciss Ciss = 360 pF TYP.
- Built-in G-S Gate Protection Diode
- High Avalanche Capability Ratings

QUALITY GRADE

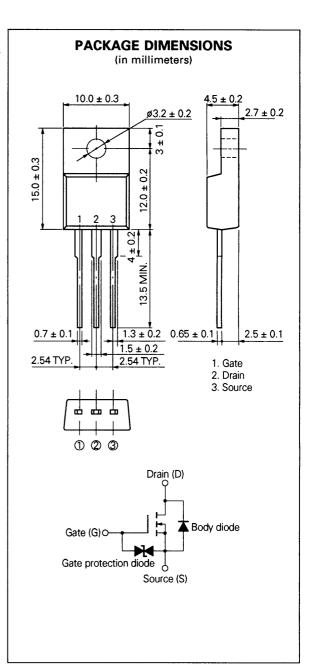
Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C)

| Drain to Source Voltage | Voss | 600 | V |
|--------------------------------------|---------------------|------------|----|
| Gate to Source Voltage | Vgss | ±30 | V |
| Drain Current (DC) | ID(DC) | ±2.0 | Α |
| Drain Current (pulse) | D(pulse)* | ±8.0 | Α |
| Total Power Dissipation (Tc = 25 °C) | P _{T1} | 30 | W |
| Total Power Dissipation (Ta = 25 °C) | Рт2 | 2.0 | W |
| Channel Temperature | Tch | 150 | °C |
| Storage Temperature | T _{stg} -5 | 55 to +150 | °C |
| Single Avalanche Current | las** | 3.0 | Α |
| Single Avalanche Energy | Eas** | 96 | mJ |
| * 504/ 40 5 . 0 1 / 40/ | | | |

* PW \leq 10 μ s, Duty Cycle \leq 1 %



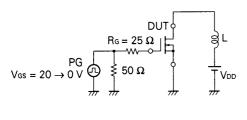
^{**} Starting Tch = 25 °C, Rg = 25 Ω , Vgs = 20 V \rightarrow 0

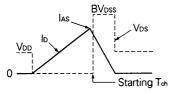


ELECTRICAL CHARACTERISTICS (Ta = 25 °C)

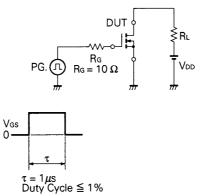
| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT | TEST CONDITIONS | |
|-------------------------------------|----------|------|------|------|------|--|--|
| Drain to Source On-state Resistance | RDS(on) | | 2.8 | 4.2 | Ω | Vgs = 10 V, lo = 1 A | |
| Gate to Source Cutoff Voltage | Vgs(off) | 2.0 | | 4.0 | V | Vps = 10 V, lp = 1 mA | |
| Forward Transfer Admittance | y fs | 0.5 | 1.3 | | S | VDS = 10 V, ID = 1 A | |
| Drain Leakage Current | loss | | | 100 | μΑ | Vps = 600 V, Vgs = 0 | |
| Gate to Source Leakage Current | lgss | | | ±10 | μΑ | Vgs = ±30 V, Vps = 0 | |
| Input Capacitance | Ciss | | 360 | | pF | V _{DS} = 10 V | |
| Output Capacitance | Coss | | 130 | | pF | Vgs = 0 | |
| Reverse Transfer Capacitance | Crss | | 50 | | pF | f = 1 MHz | |
| Turn-On Delay Time | td(on) | | 5 | | ns | V _{GS(on)} = 10 V | |
| Rise Time | tr | | 6 | | ns | V _{DD} = 150 V | |
| Turn-Off Delay Time | td(off) | | 60 | | ns | In = 1 A, Rg = 10 Ω RL = 150 Ω | |
| Fall Time | tr | | 20 | | ns | - NL = 150 12 | |
| Total Gate Charge | QG | | 17 | | nC | Vgs = 10 V | |
| Gate to Source Charge | Qgs | | 3 | | nC | IF = 2 A | |
| Gate to Drain Charge | QgD | | 10 | | nC | VDD = 400 V | |
| Diode Forward Voltage | VF(S-D) | | 0.85 | | V | IF = 2 A, VGS = 0 | |
| Reverse Recovery Time | trr | | 270 | | ns | I _F = 2 A, V _{GS} = 0 di/dt = 50 A/μs | |
| Reverse Recovery Charge | Qrr | | 1.4 | | μC | | |

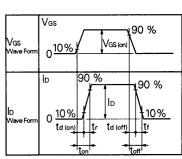
Test Circuit 1: Avalanche Capability



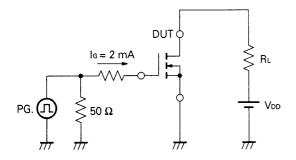


Test Circuit 2: Switching Time

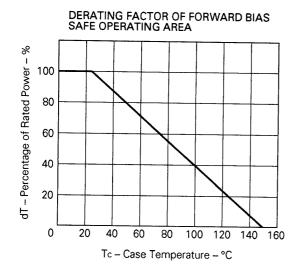


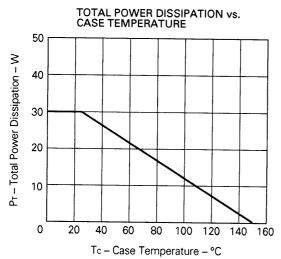


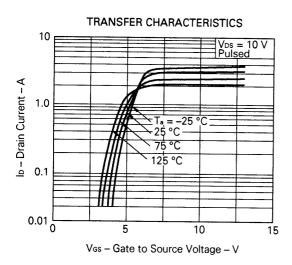
Test Circuit 3: Gate Charge

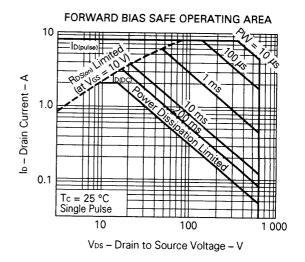


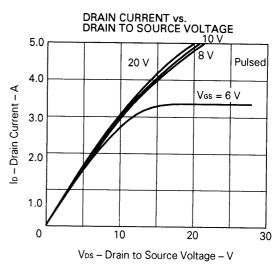
TYPICAL CHARACTERISTICS (Ta = 25 °C)



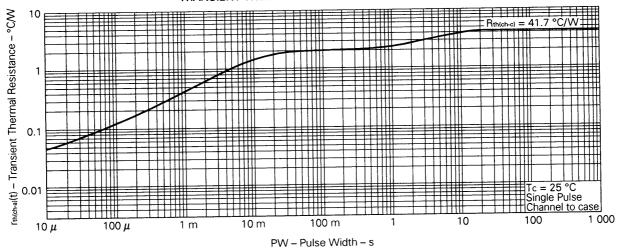




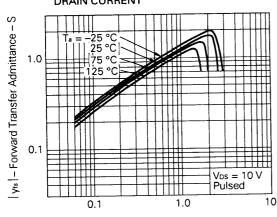




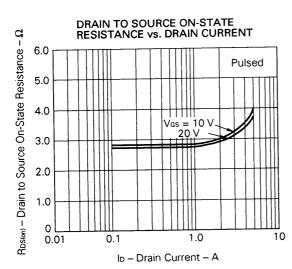
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



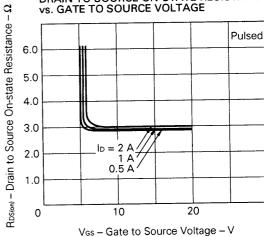


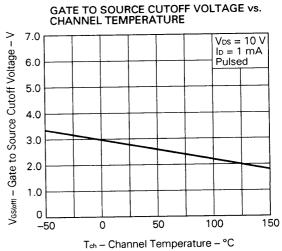


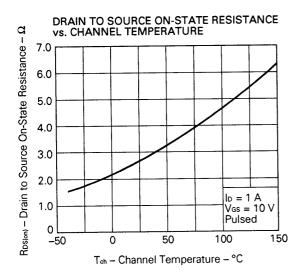
In - Drain Current - A



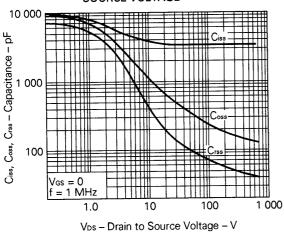
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



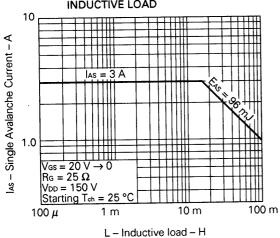




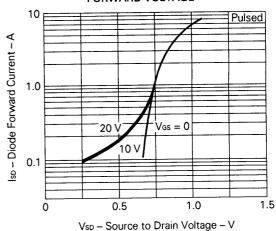




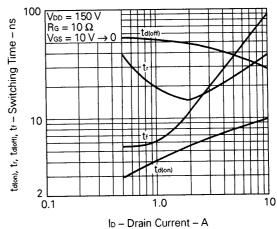
SINGLE AVALANCHE CURRENT vs. INDUCTIVE LOAD



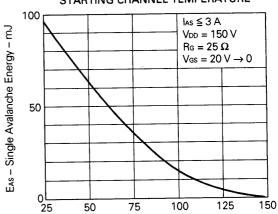
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



SWITCHING TIME vs. DRAIN CURRENT



SINGLE AVALANCHE ENERGY vs. STARTING CHANNEL TEMPERATURE



Starting T_{ch} - Starting Channel Temperature - °C

Reference

| Application note name | No. | | |
|--|----------|--|--|
| Safe operating area of Power MOS FET. | TEA-1034 | | |
| Application circuit using Power MOS FET. | TEA-1035 | | |
| Quality control of NEC semiconductors devices. | TEI-1202 | | |
| Quality control guide of semiconductors devices. | MEI-1202 | | |
| Assembly manual of semiconductors devices. | IEI-1207 | | |

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